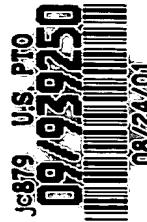


Docket No.: J&R-0714

J. B.  
3/7/02

#5

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE



Applicant : RALF ARNOLD ET AL.

Filed : Concurrently herewith

Title : METHOD FOR TESTING A PROGRAM-CONTROLLED UNIT BY  
AN EXTERNAL TEST DEVICE

INFORMATION DISCLOSURE STATEMENT

Hon. Commissioner of Patents and Trademarks,  
Washington, D.C. 20231

Sir:

In accordance with 37 C.F.R. 1.98 copies of the following patents and/or publications are submitted herewith:

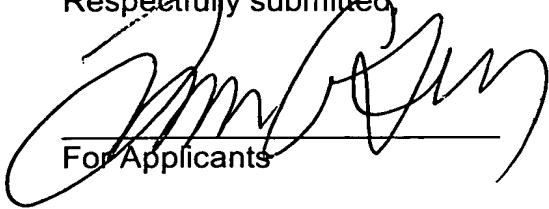
German Patent Application DE 198 33 208 C 1 (Florian Schamberger et al.), dated October 28, 1999, integrated circuit with a self-testing device to do a self-test of the integrated circuit;

German Published, Non-Prosecuted Patent Application DE 198 35 258 A 1 (Robert Kaiser et al.), dated October 2, 2000, integrated circuit with a self-testing device;

Hans Dieter Oberle: "Selbsttest bei Mikroprozessorsystemen" (self-testing of micro-processor systems), issued in the magazine "Elektronik", April 22, 1983, pages 61-63;

If no translation of pertinent portions of any foreign language patents or publications mentioned above is included with the aforementioned copies of those applications, patents and/or publications, it is because no existing translation is readily available to the applicant.

Respectfully submitted,



For Applicants

Date: August 24, 2001

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